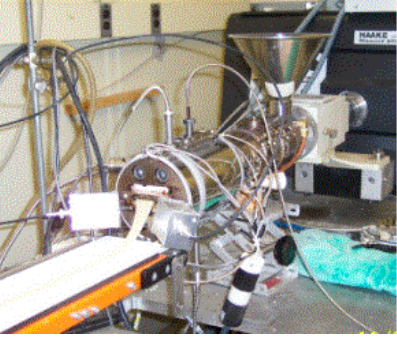


Multifunctional Monitoring of Polymer/Clay Compounding Using Dielectric, Optical and Fluorescence Measurements

Anthony J. Bur, Yu-Hsin Lee, Steven C. Roth and Paul R. Start
NIST, Polymers Division

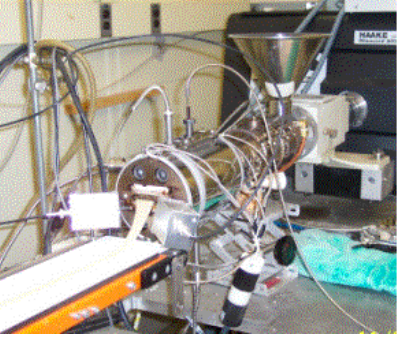
and

Paul H. Maupin
Office of Basic Energy Science, US Dept.of Energy



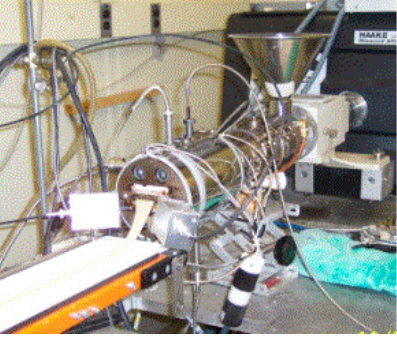
Outline

- ✓ **The NIST Dielectric Slit Die**
- ✓ **Monitoring Nylon/Clay Nanocomposites Compounding**
 - **Dielectric**
 - **Optical transmission**
 - **Fluorescence**



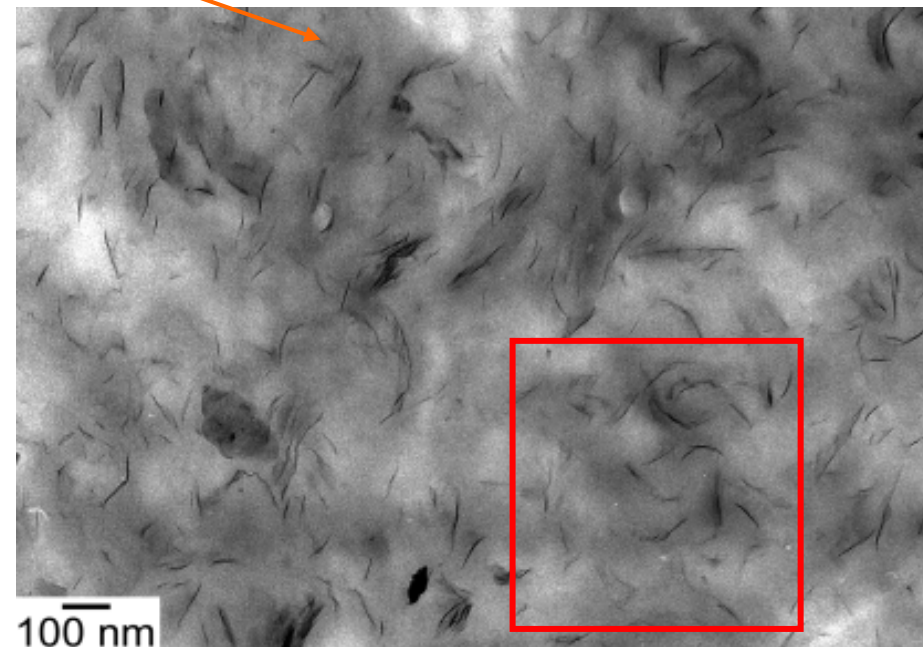
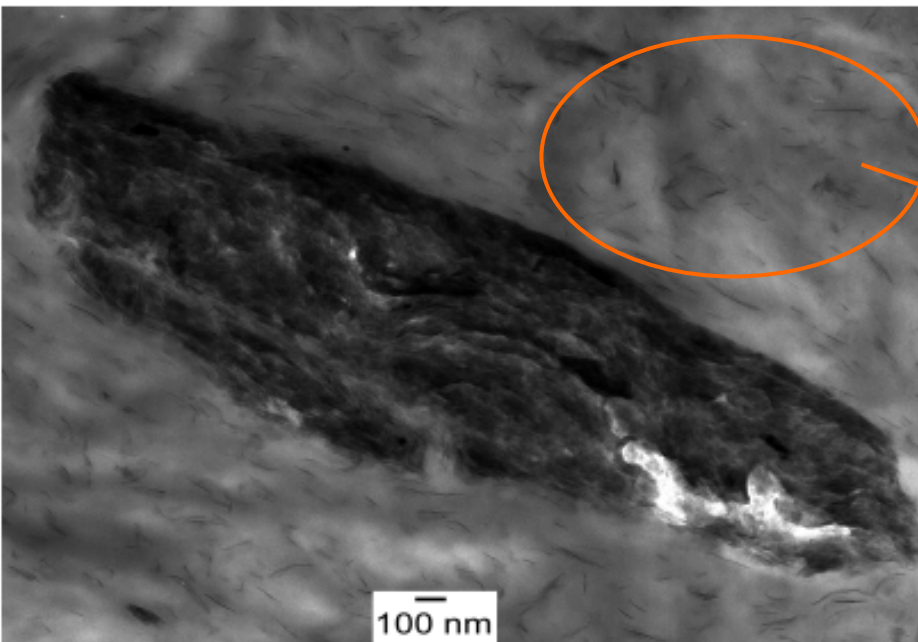
Outline

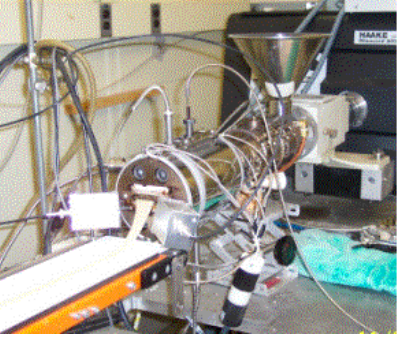
- ✓ **The NIST Dielectric Slit Die**
- ✓ **Monitoring Nylon/Clay Nanocomposites Compounding**
 - **Dielectric**
 - **Optical transmission**
 - **Fluorescence**
- ✓ **Model Development: Extent of Exfoliation**



*Outstanding Question:
What is an exfoliated clay nanocomposite?*

Nylon 6/30B clay

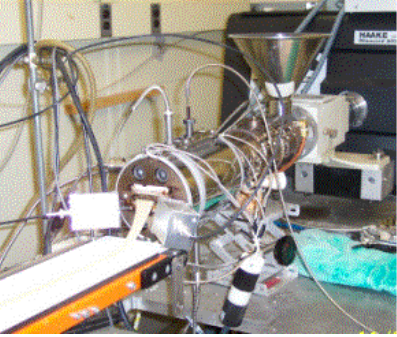




Exfoliation is the Goal

Enhanced resin-filler interface surface area yields:

- **Improved materials properties of composites with less filler material**
- **Improved mechanical properties**
 - **modulus, strength, toughness**
 - **applications: automotive, packaging**
- **Improved barrier resin behavior**
- **Improved fire retardation**

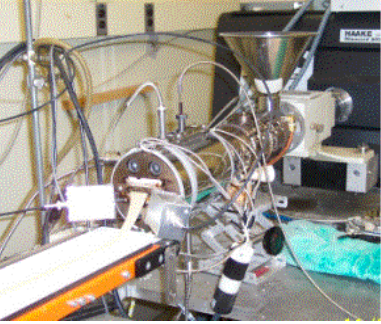


Exfoliation is the Goal

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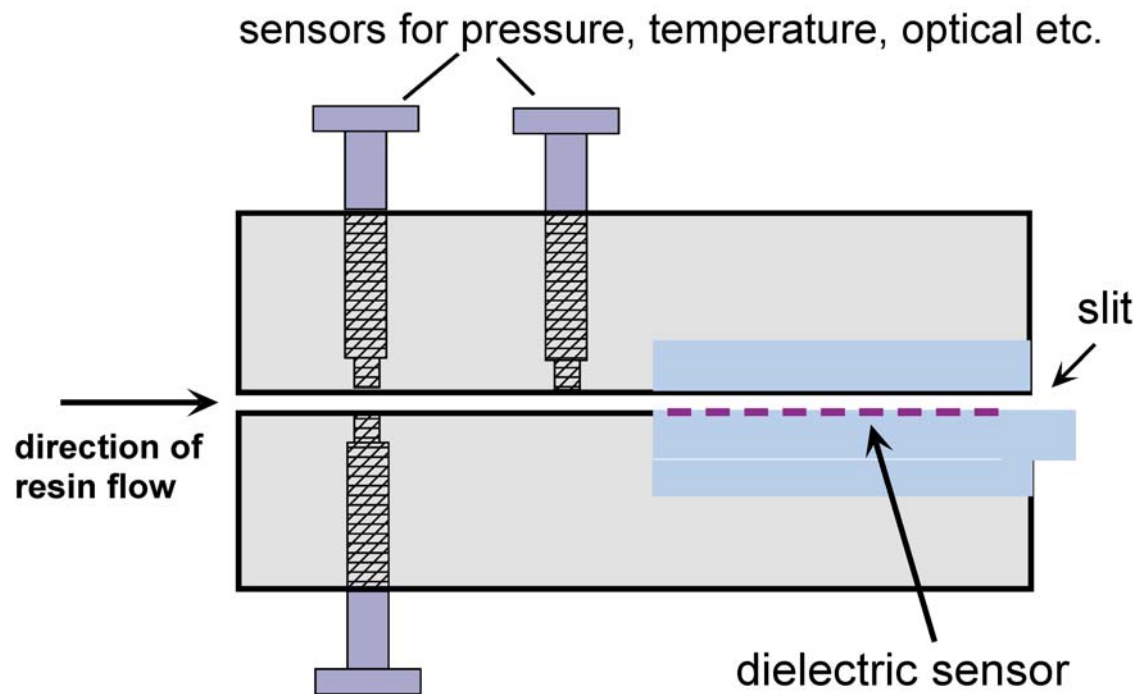
In order to control exfoliation, you must first measure it.

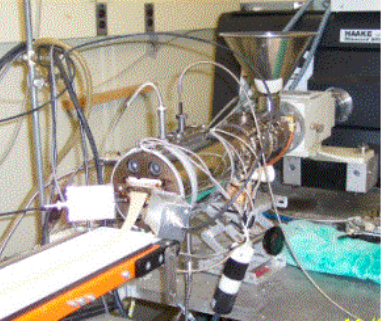


The NIST Dielectric Slit Die

Instrument Concept:

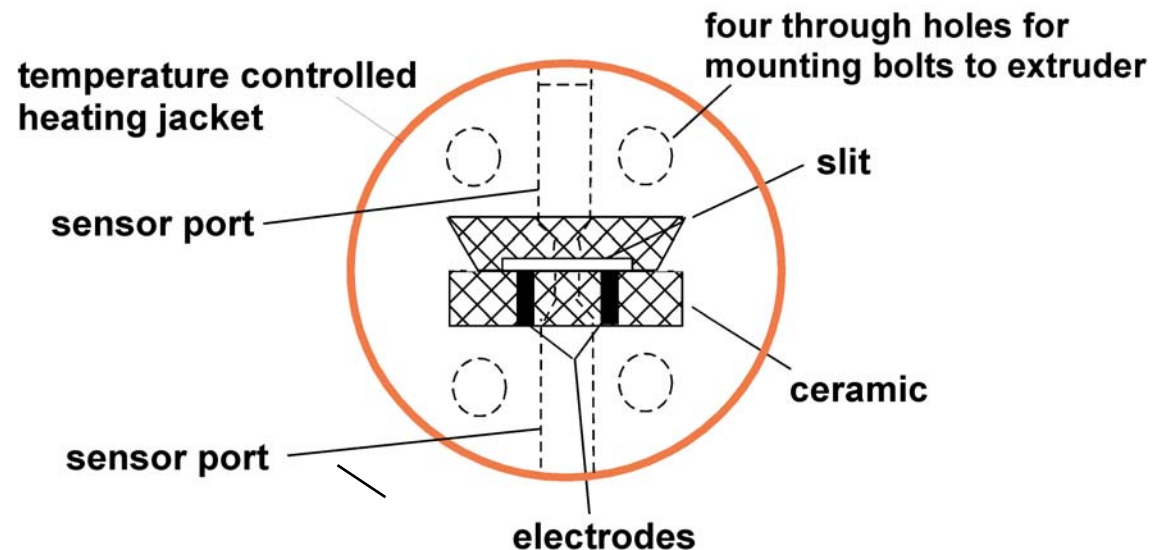
A Slit Platform for Mounting Multiple Sensors





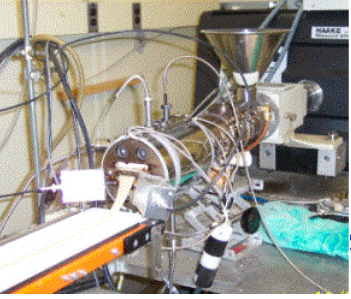
The NIST Dielectric Slit Die

Front View



Advantage of the slit configuration:

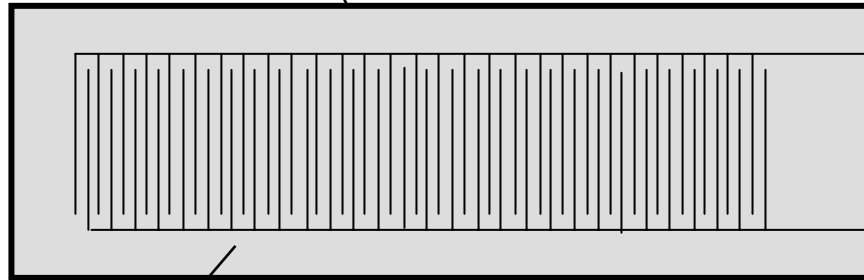
- Constant geometry sample chamber can be interrogated by multiple of sensors
- Has configuration of a slit die rheometer.



Interdigitating Electrodes

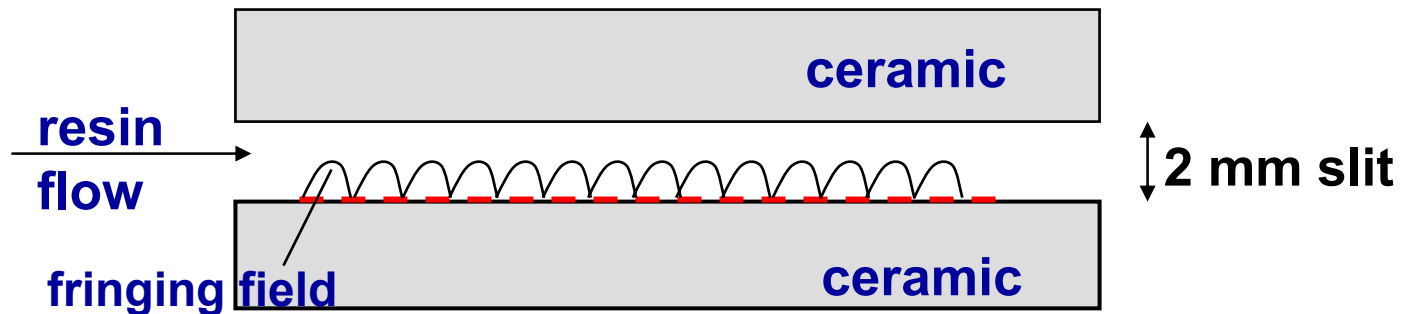
ceramic substrate

Top View

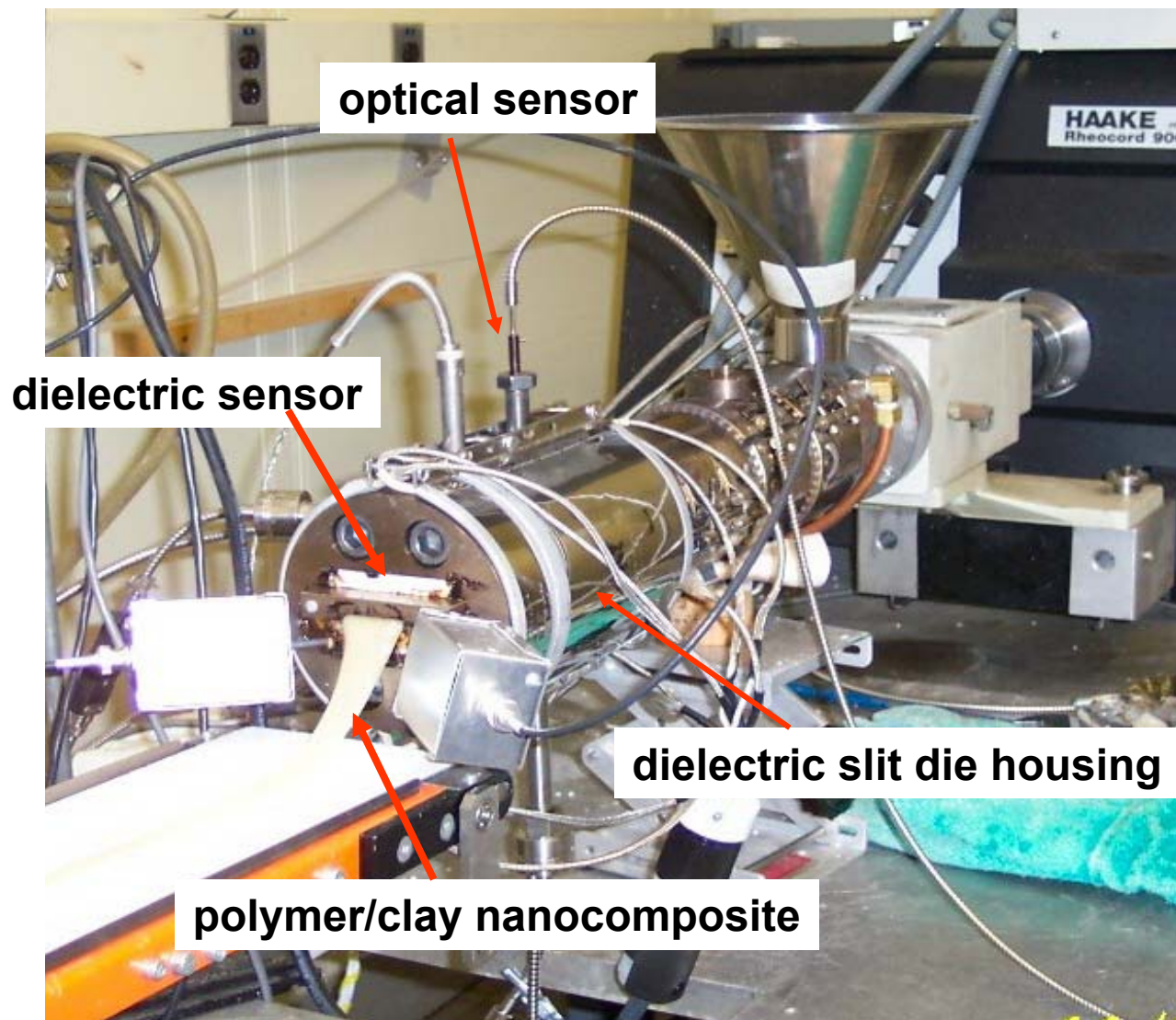


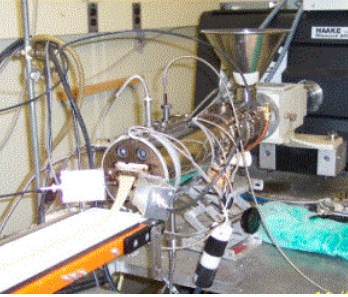
Interdigitating electrodes

Side View

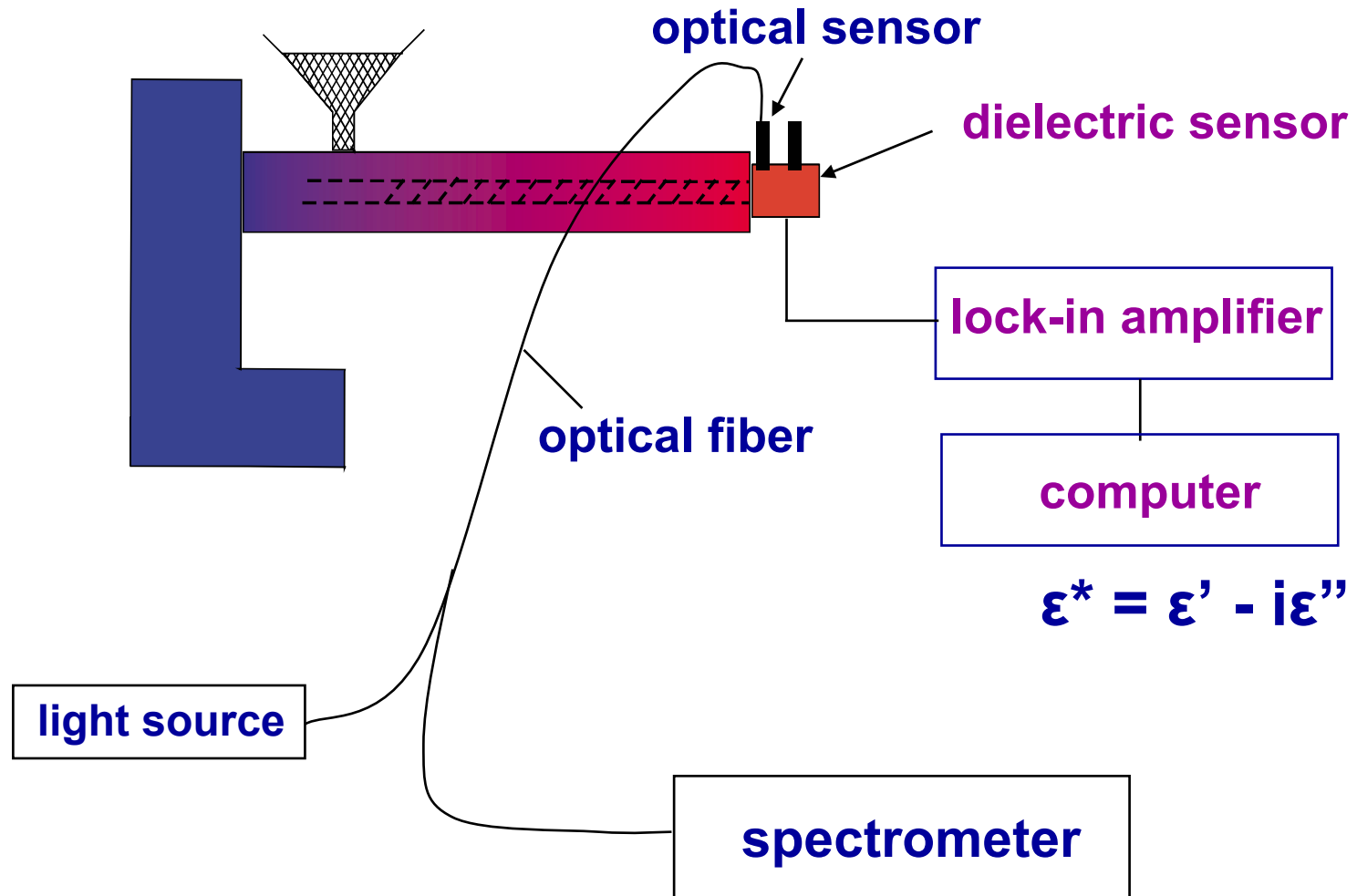


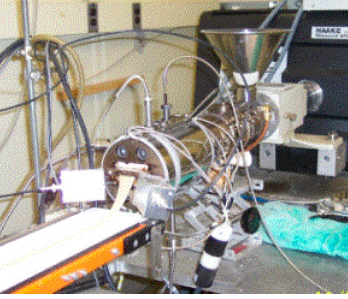
The NIST Dielectric Slit Die





Experimental Setup for Extrusion

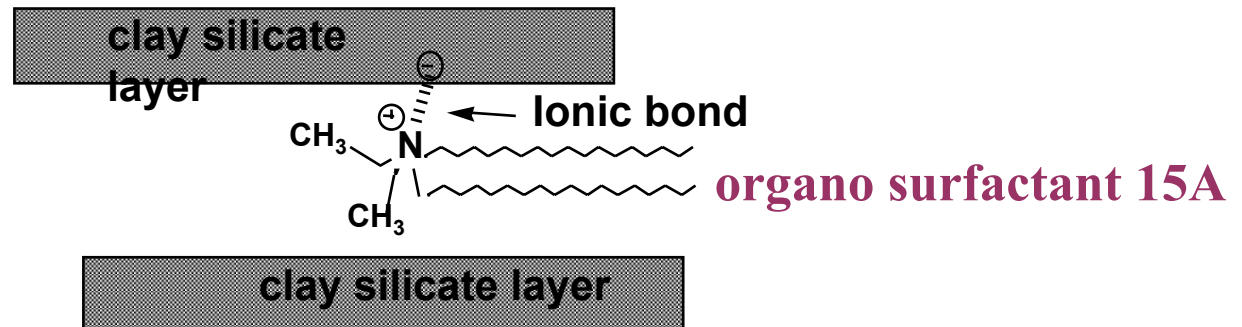


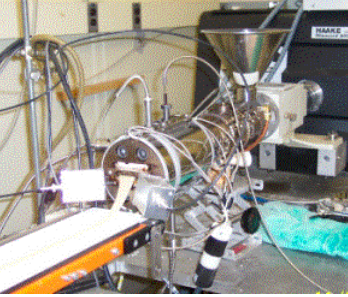


Compounding Nylon/Clay Composites

Materials:

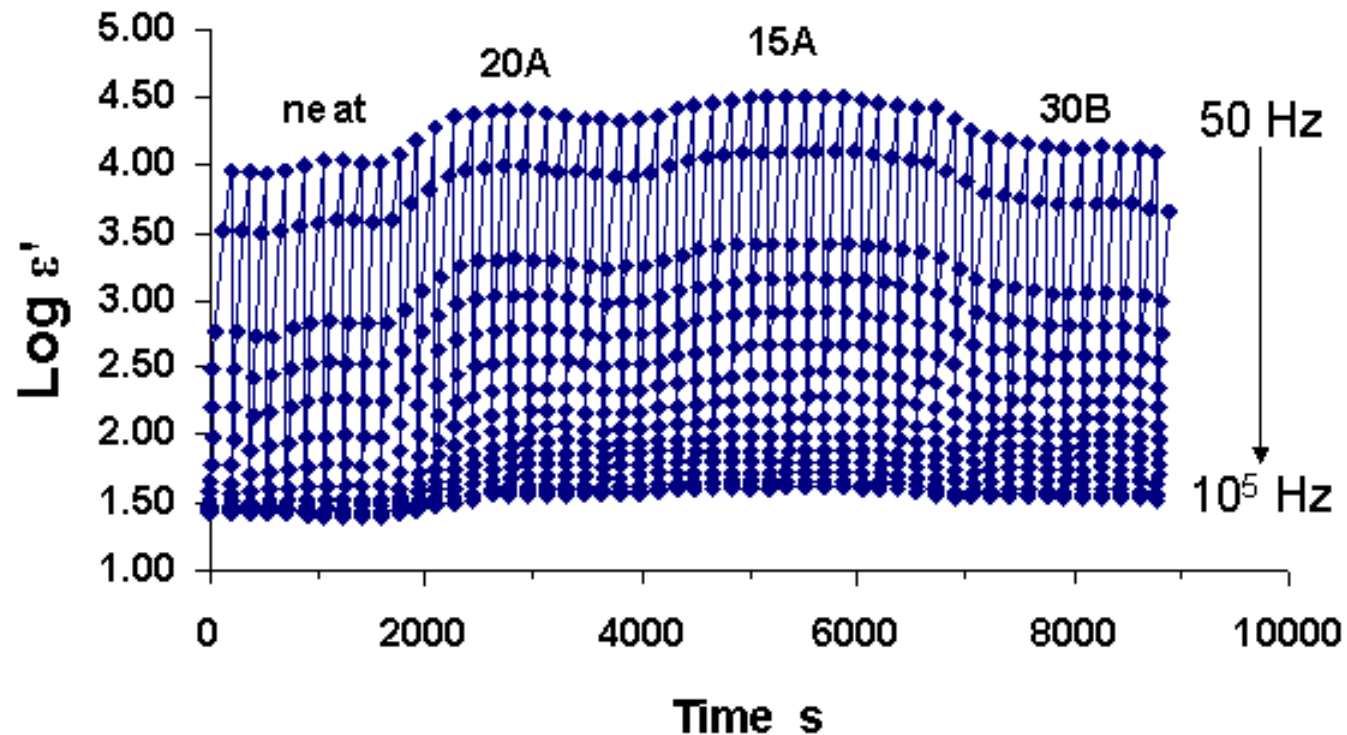
- nylon 11 and Nylon 6
- montmorillonite clays
 - ♦ natural Na⁺ clay (aggregate composite)
 - ♦ three organo modified clays
15A, 20A, 30B (partially exfoliated)

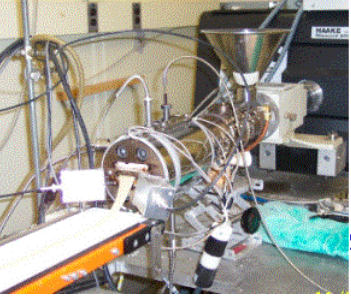




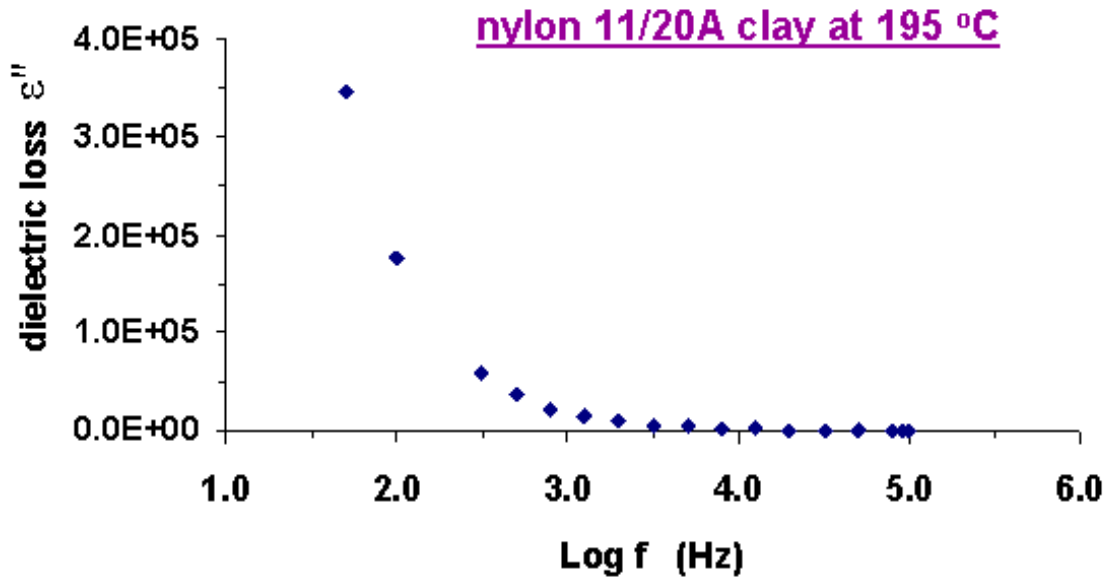
Compounding Nylon/Clay Composites: Dielectric Monitoring

nylon 11 at 195 °C





Analyzing Dielectric Data

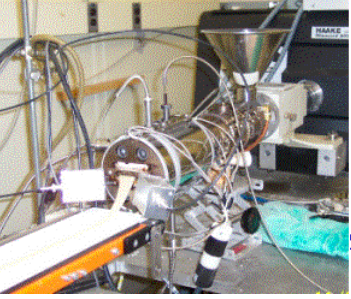


Data are fit with dispersion function:

$$\epsilon^* = -\frac{i\sigma}{\omega\epsilon_0} + \epsilon_\infty + \underbrace{\sum_j \frac{(\epsilon_0 - \epsilon_\infty)_j}{[1 + (i\omega\tau_j)^{1-\alpha_j}]}}_{\text{Cole-Cole dielectric relaxation}}$$

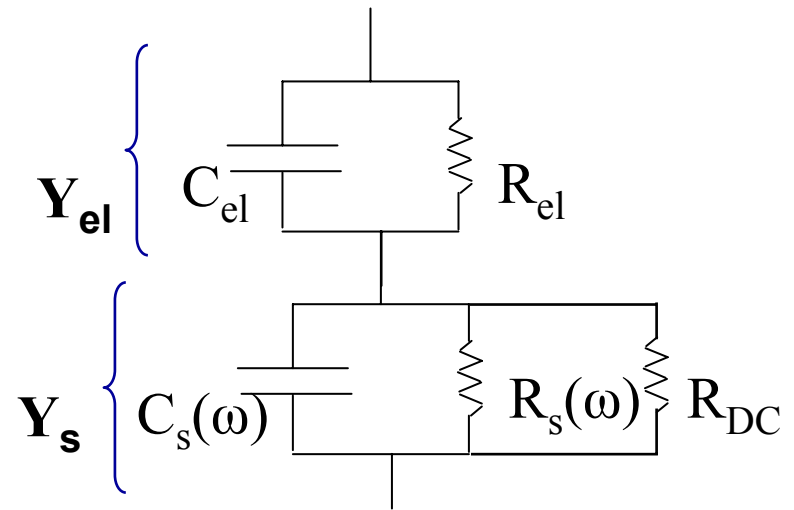
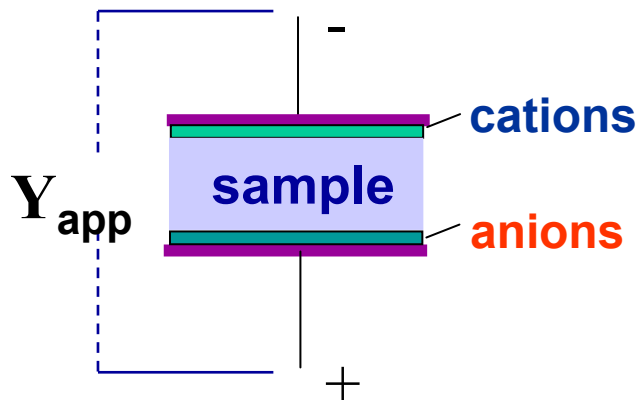
DC conductivity

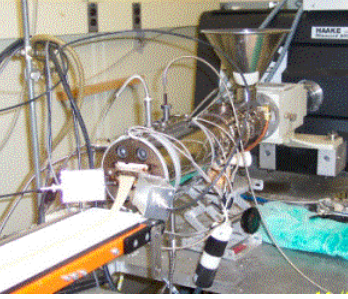
Cole-Cole dielectric relaxation



Analyzing Dielectric Data

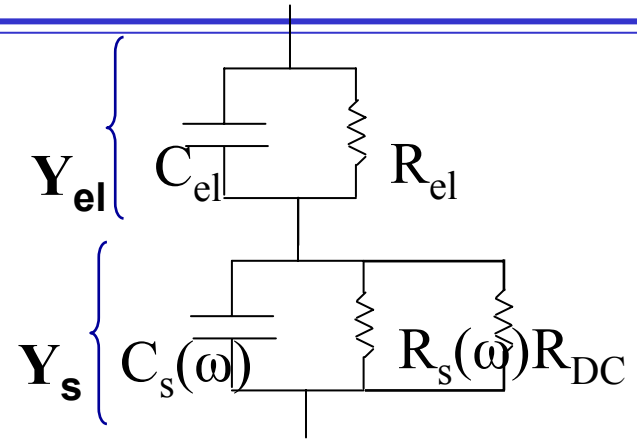
Electrical impedance model:





Analyzing Dielectric Data

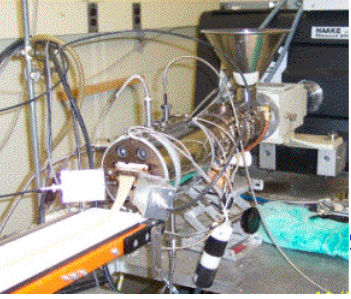
Electrical impedance model:



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DC conductivity

Cole-Cole dielectric relaxation



Analyzing Dielectric Data

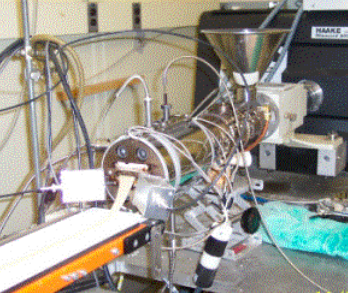
$$\epsilon^* = -\frac{i\sigma}{\omega\epsilon_0} + \epsilon_\infty + \underbrace{\sum_j \frac{(\epsilon_0 - \epsilon_\infty)_j}{[1 + (i\omega\tau_j)^{1-\alpha_j}]}}_{\text{Cole-Cole dielectric relaxation}}$$

DC conductivity

Cole-Cole dielectric relaxation

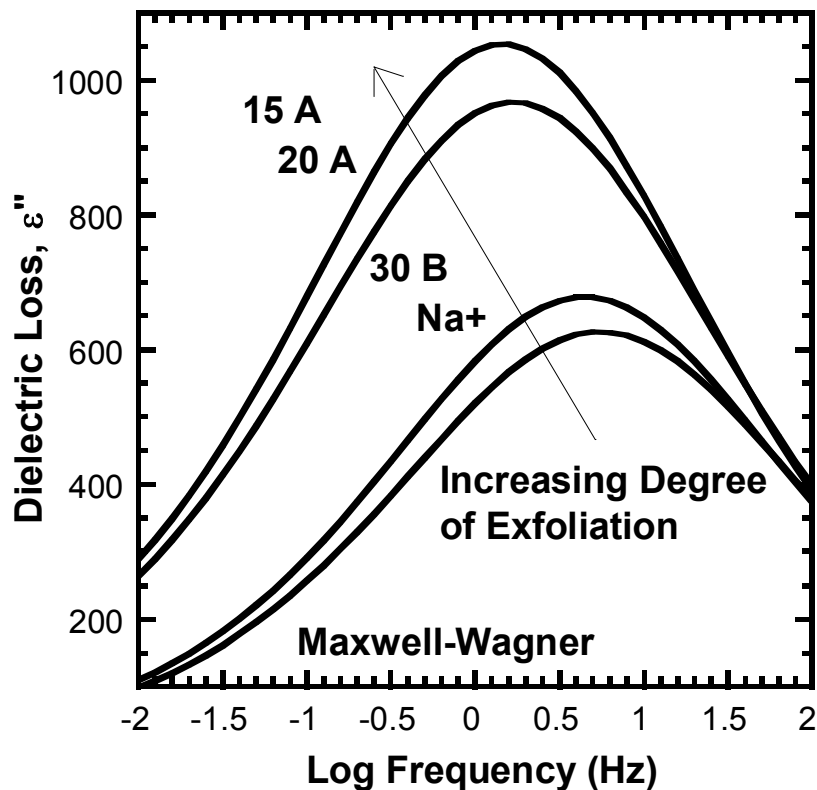
Analysis protocol:

- Examine raw data for relaxation phenomena noting magnitude and position on frequency scale
- Carry out non-linear regression curve fitting to retrieve relaxation parameters

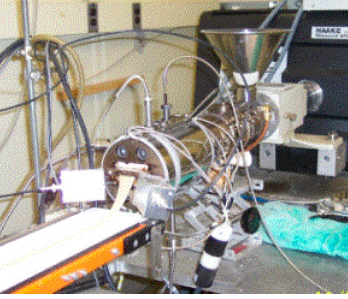


Maxwell Wagner Relaxation

nylon 11 at 195 °C

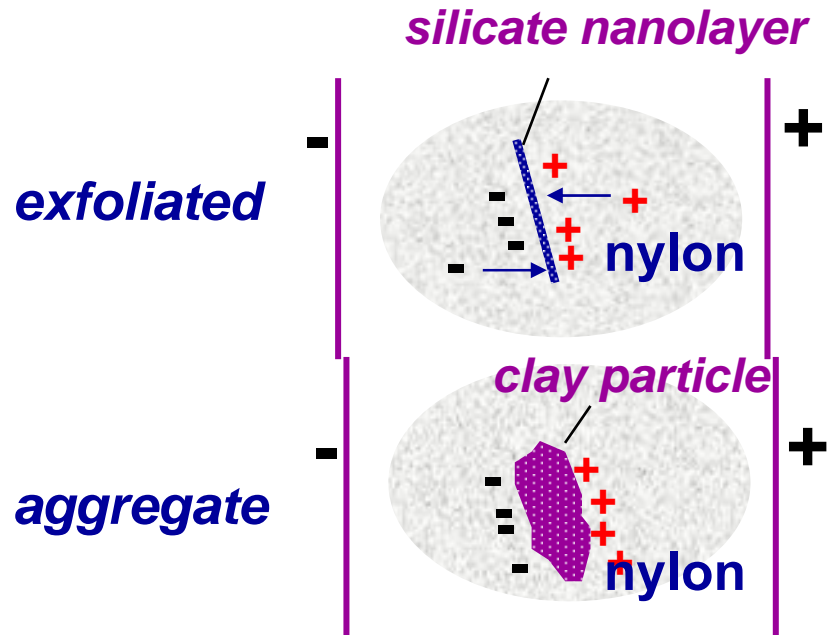


	Log f_{MW}
Nylon 11 at 198 °C	--
Nylon 11/Na+	0.74
Nylon 11/30B	0.62
Nylon 11/20A	0.24
Nylon 11/15A	0.16
Nylon 6 at 242 °C	--
Nylon 6/15A	1.98
Nylon 6/30B	1.10



Maxwell Wagner Relaxation

Reflects RC Time Constant for Charging Polymer/Clay Interface



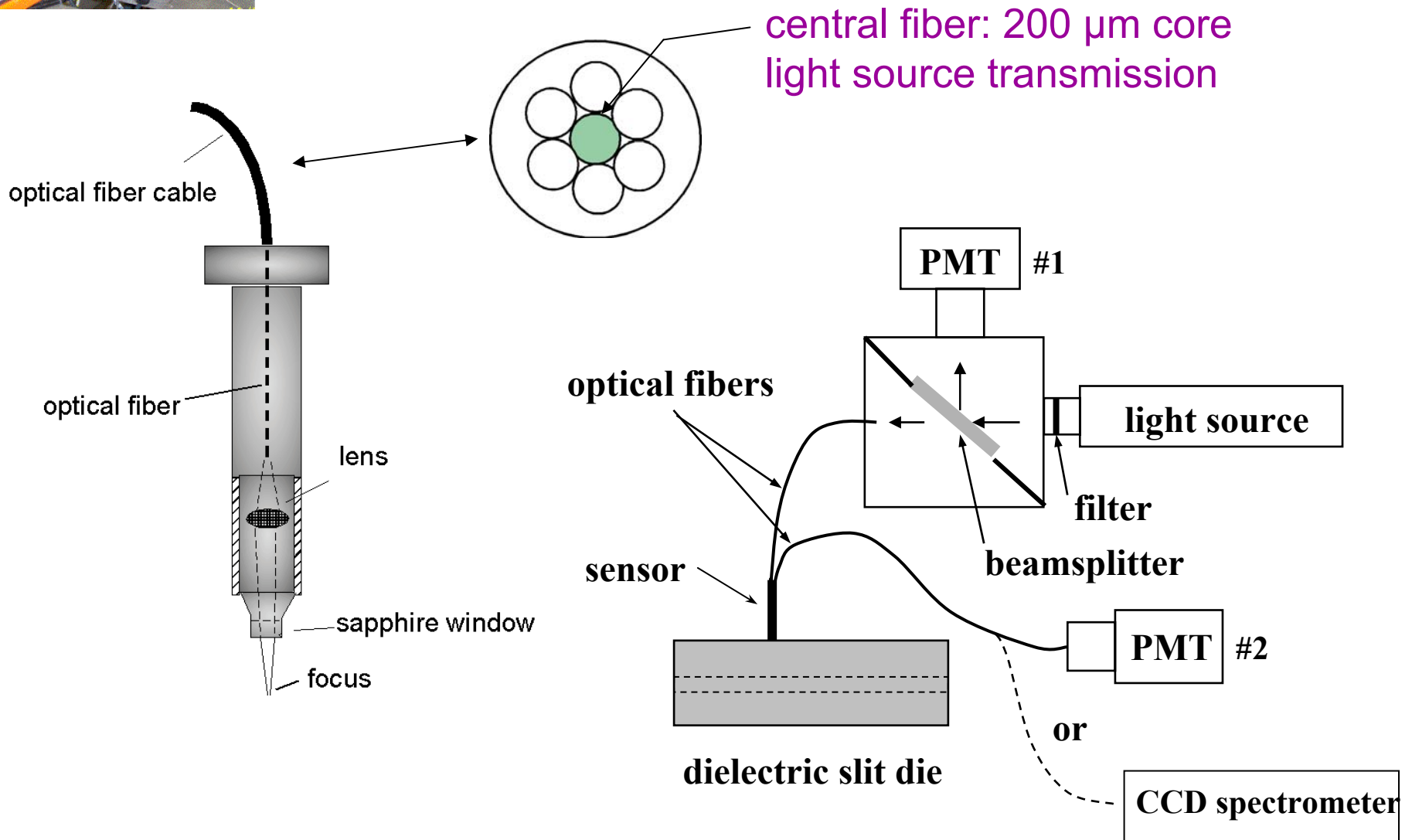
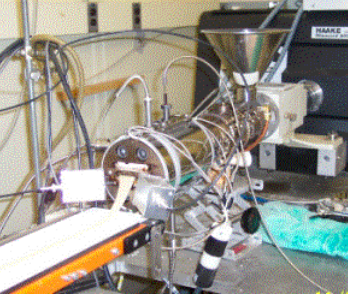
$$RC = \tau_{MW} = (2\pi f_{MW})^{-1}$$

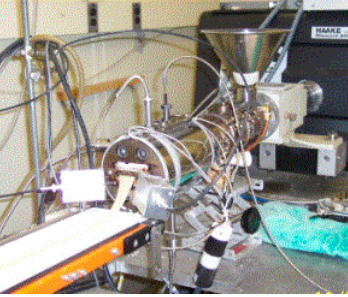
R = resistance of nylon (constant)

C = capacitance of clay particle
(increases with exfoliation)

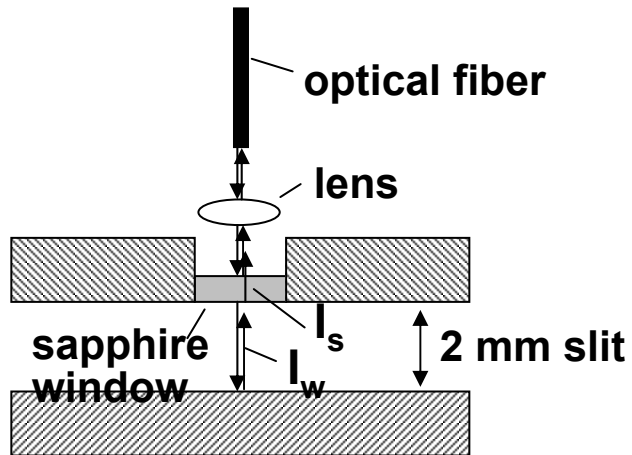
τ_{MW} large or f_{MW} small
for exfoliated composite

Compounding Nylon/Clay Composites: Optical Monitoring

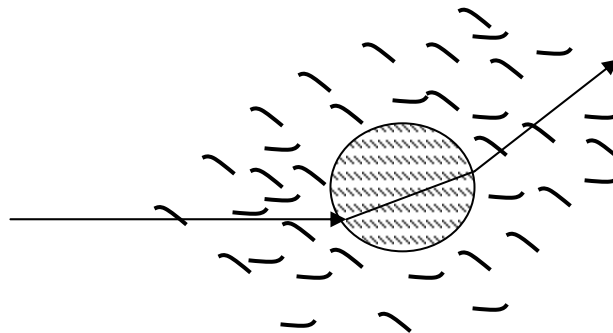
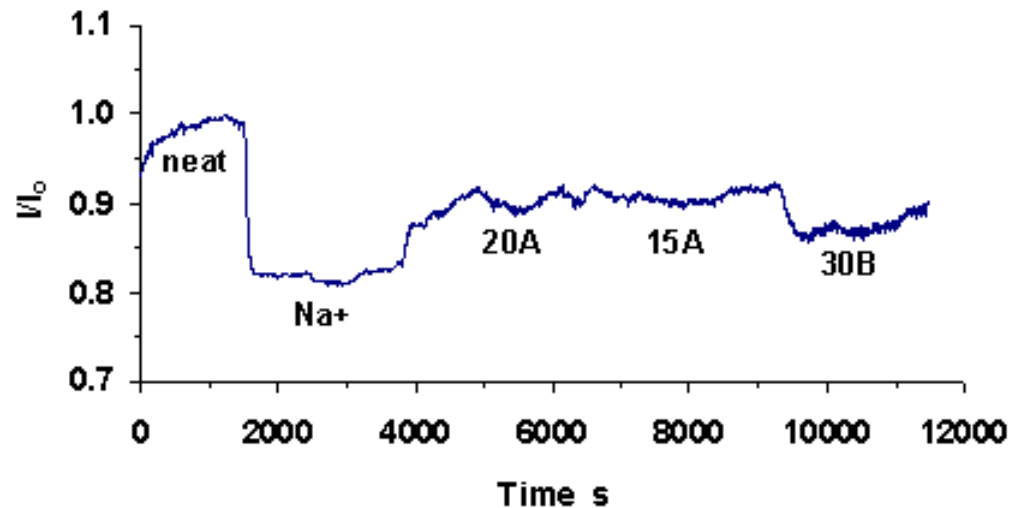


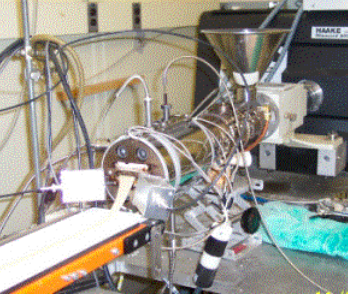


Compounding Nylon/Clay Composites: Optical Monitoring

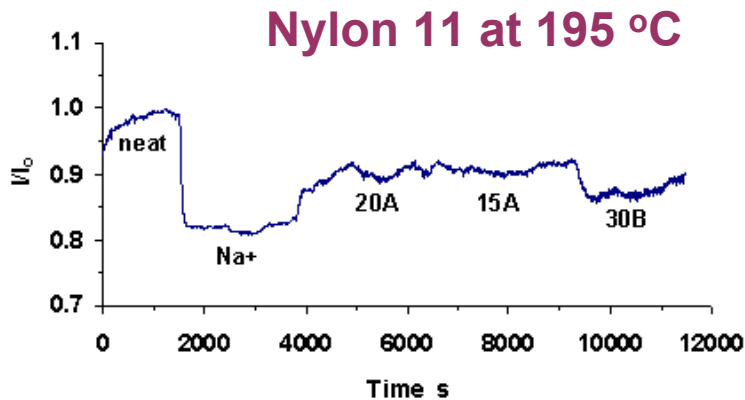


Nylon 11 at 195 °C



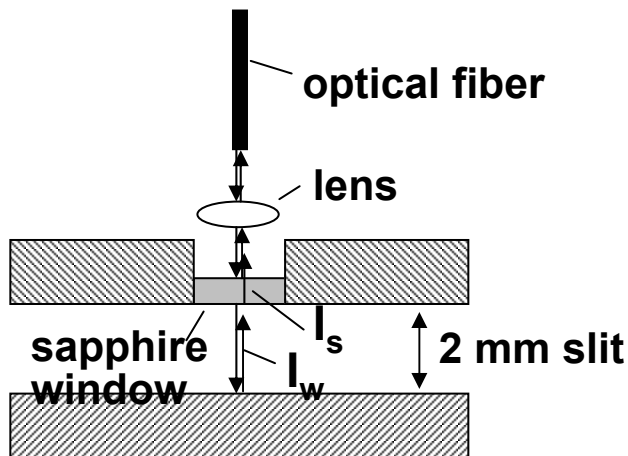


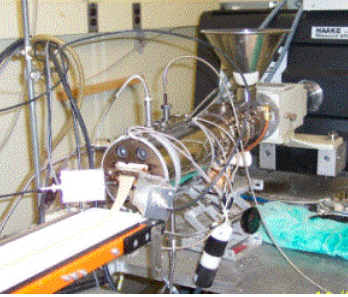
Compounding Nylon/Clay Composites: Optical Monitoring



$$I_t = I_o e^{-\gamma\phi}$$

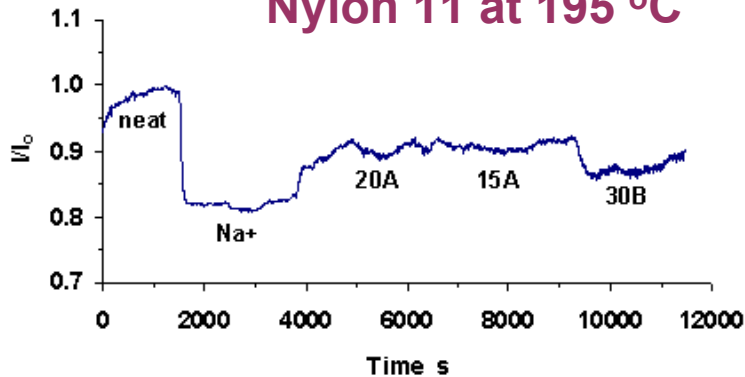
ϕ = volume fraction of
aggregate





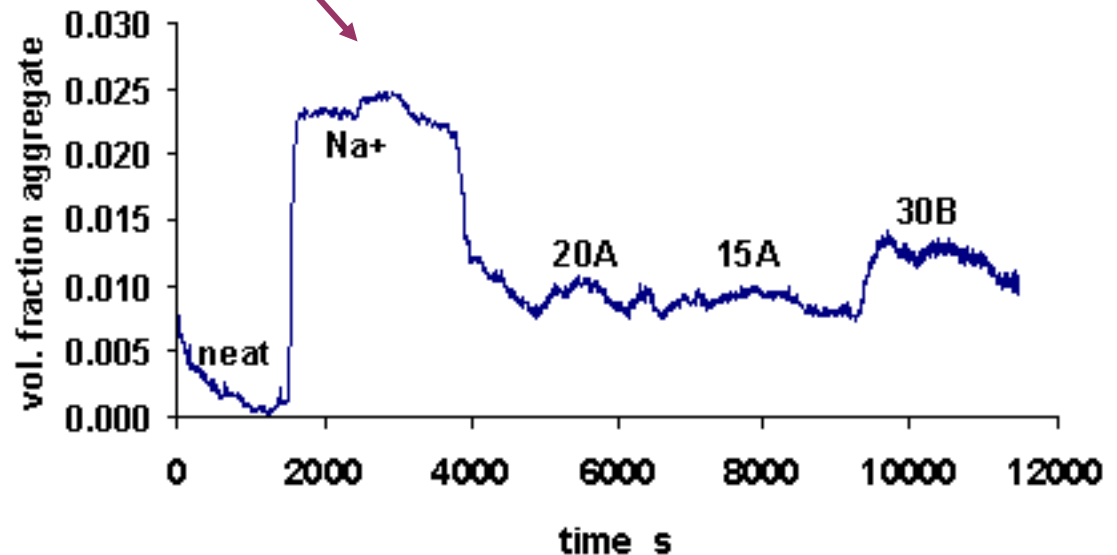
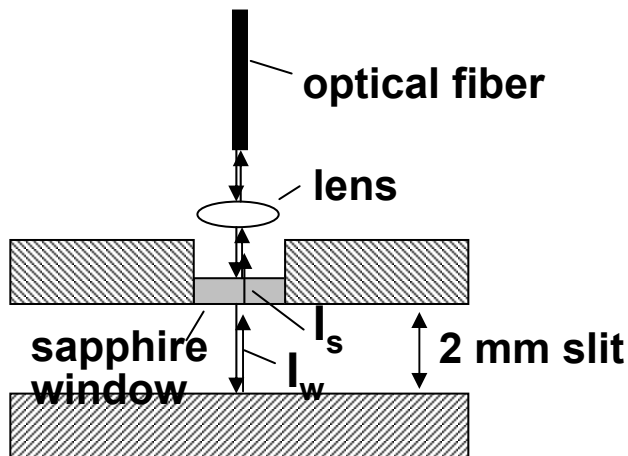
Compounding Nylon/Clay Composites: Optical Monitoring

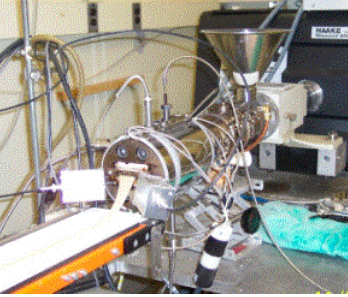
Nylon 11 at 195 °C



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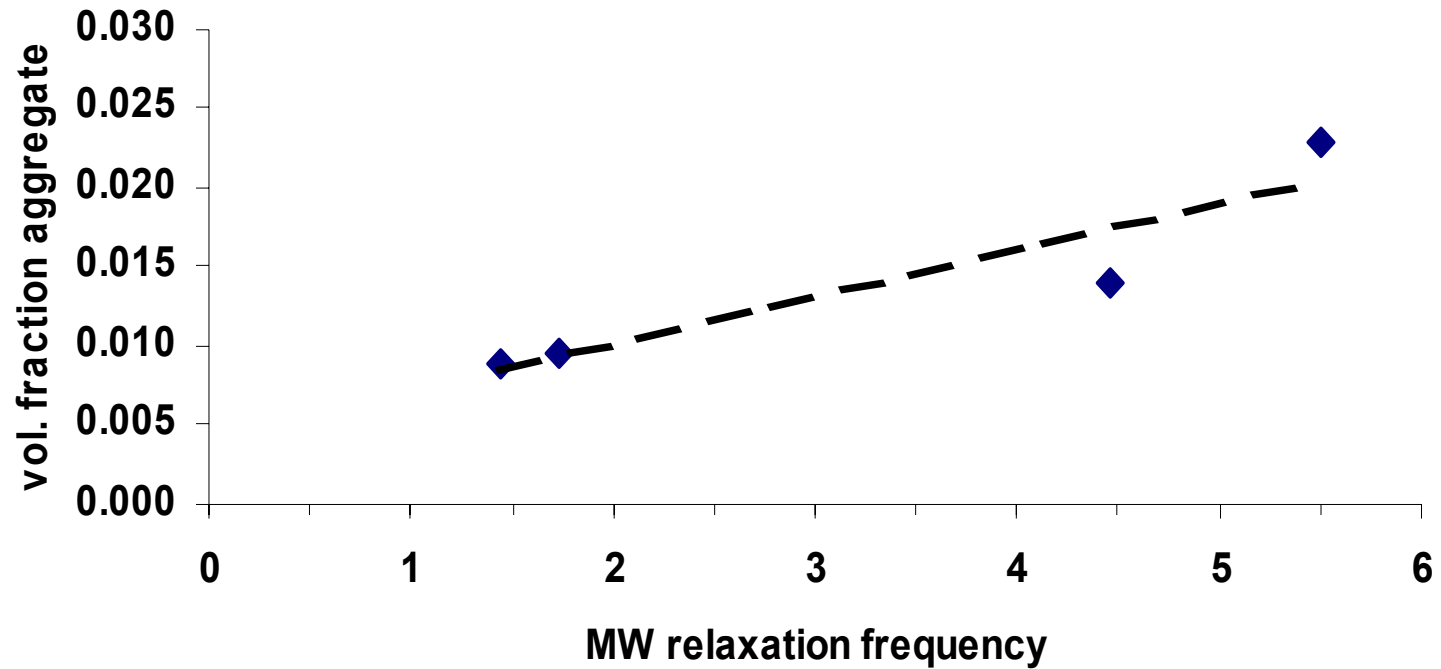


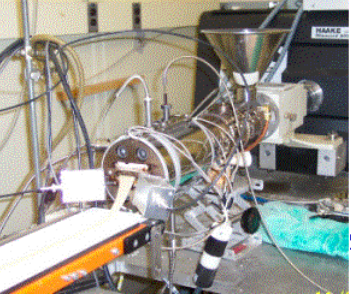


Compounding Nylon/Clay Composites

Extent of Exfoliation

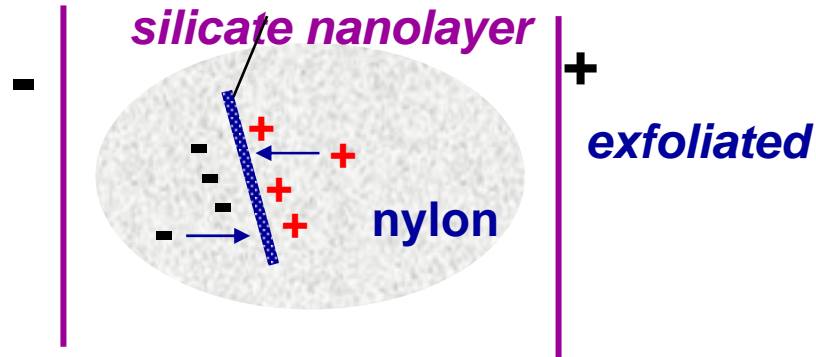
nylon 11/clay nanocomposites



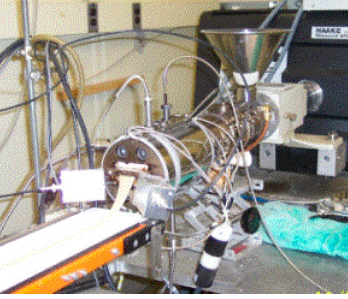


Compounding Nylon/Clay Composites

Developing an Extent of Exfoliation Scale

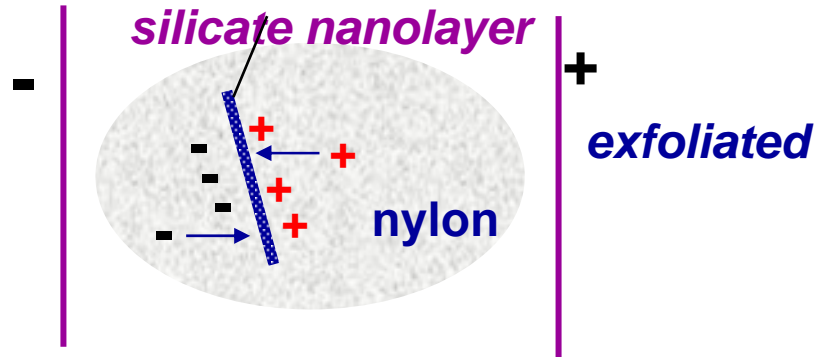


Calculate time constant for charging capacitor



Compounding Nylon/Clay Composites

Developing an Extent of Exfoliation Scale



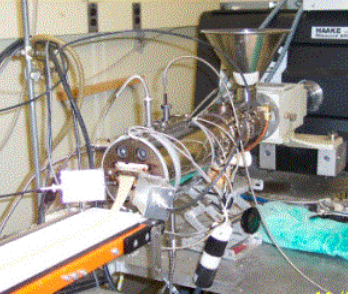
time constant: $RC = \tau_{MW}$ or $\rho\epsilon = \tau_{MW}$

drift velocity: $bv = qE$ where $b = 6\pi\eta a$ (Stokes)

Ohm's law: $nqv\rho = E$

Extent of Exfoliation:

$$\frac{n_o C}{nC_o} = \frac{n_o q^2 \tau_{MW}}{6\pi\epsilon_o \eta a}$$



Compounding Nylon/Clay Composites

Developing an Extent of Exfoliation Scale

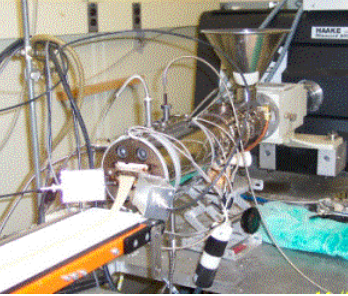
Extent of Exfoliation:

$$\frac{n_o C}{nC_o} = \frac{n_o q^2 \tau_{MW}}{6\pi \epsilon_o \eta a}$$

η is molecular viscosity – obtain from diffusion constant or dielectric relaxation time

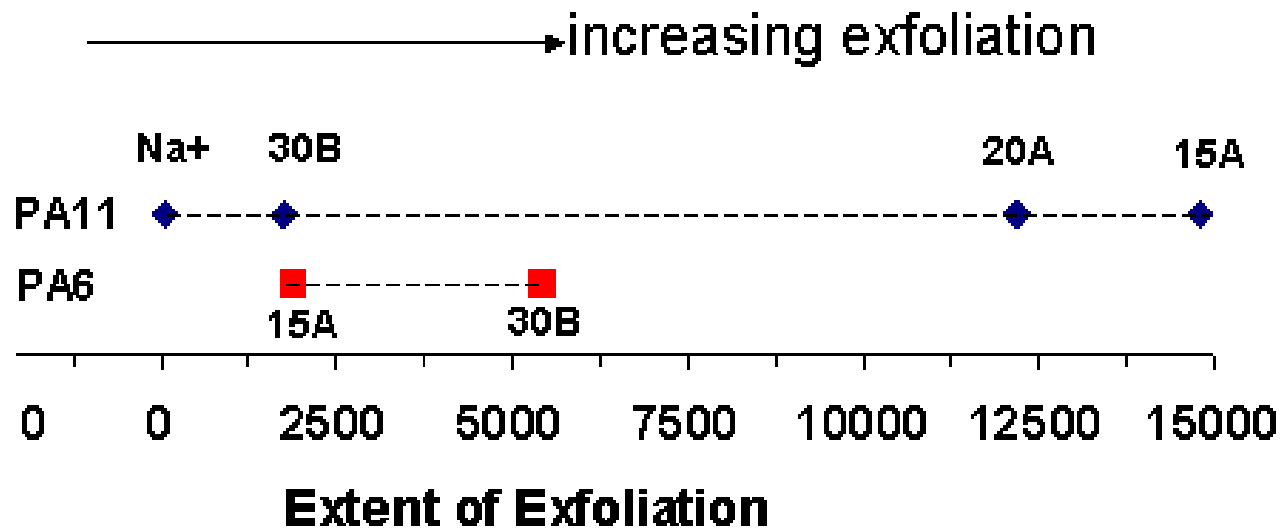
From dielectric measurements:

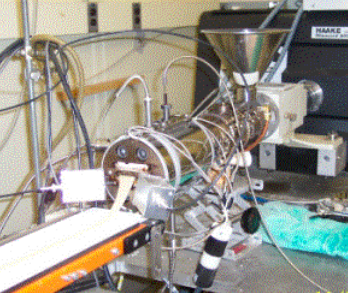
$$\tau_r = \frac{8\pi\eta a^3}{2kT}$$



An Extent of Exfoliation Scale

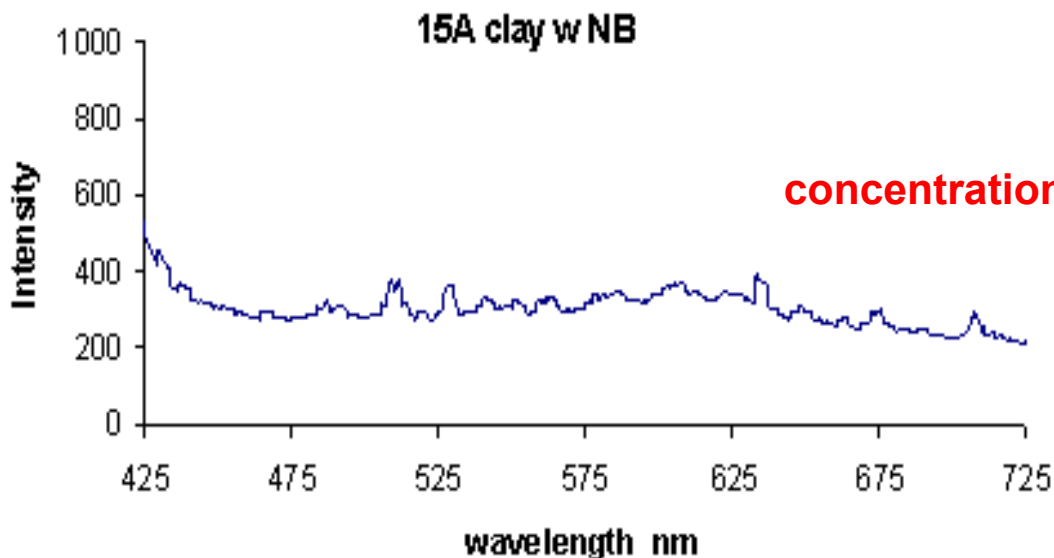
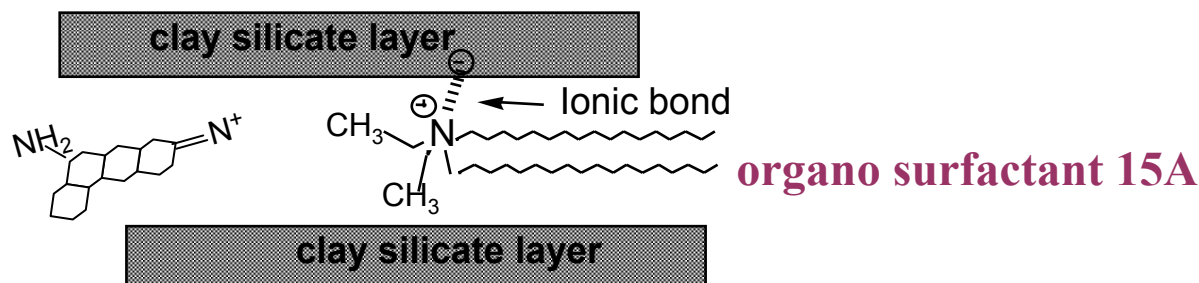
Use τ_r from γ relaxation of nylon:



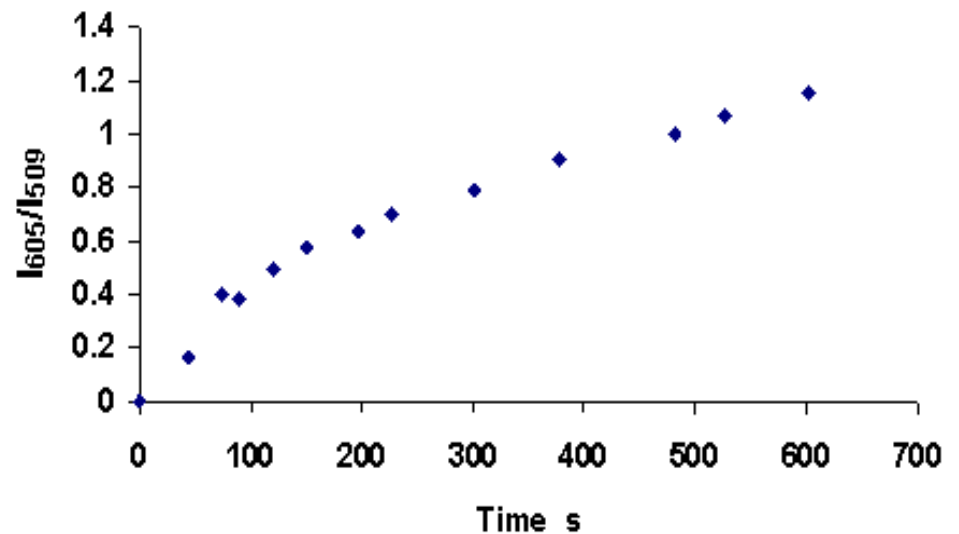
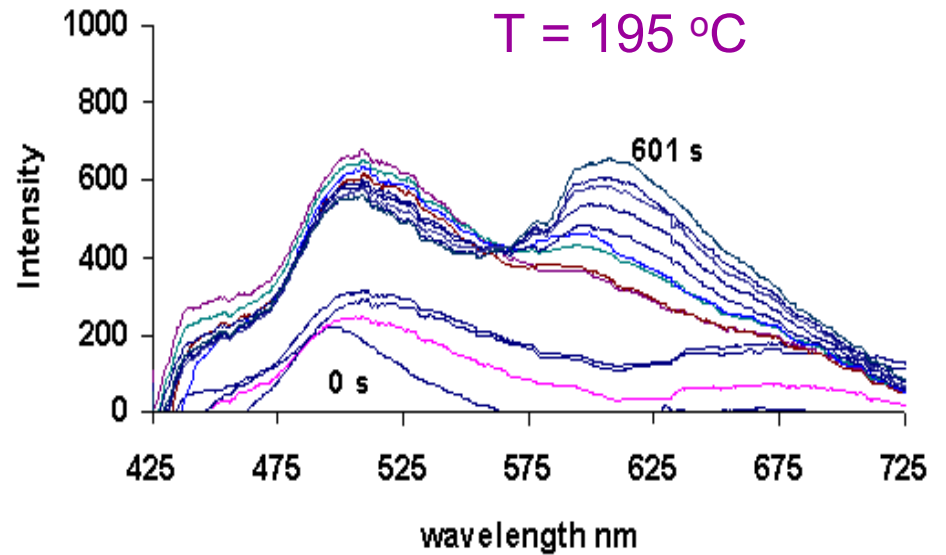
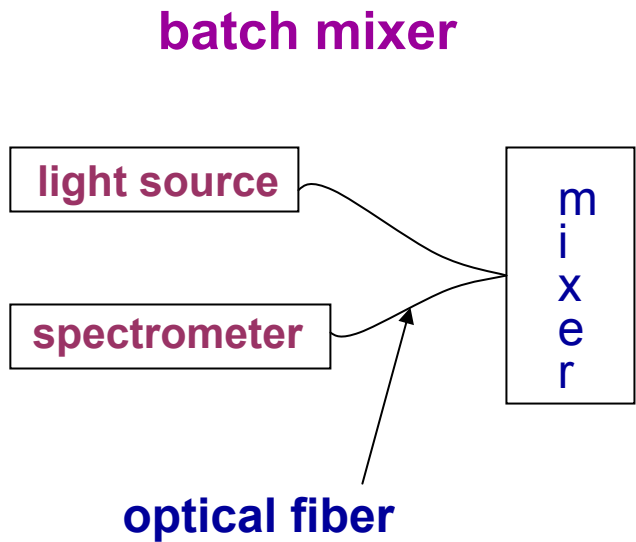


Compounding Nylon/Clay Composites: Fluorescence Monitoring

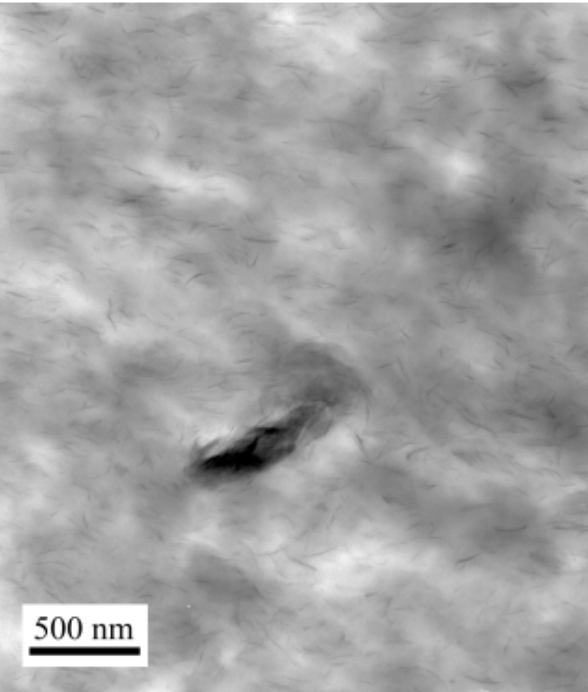
nile blue replaces
5% of surfactant
by ion exchange



Compounding Nylon 11/15A Nile blue dye

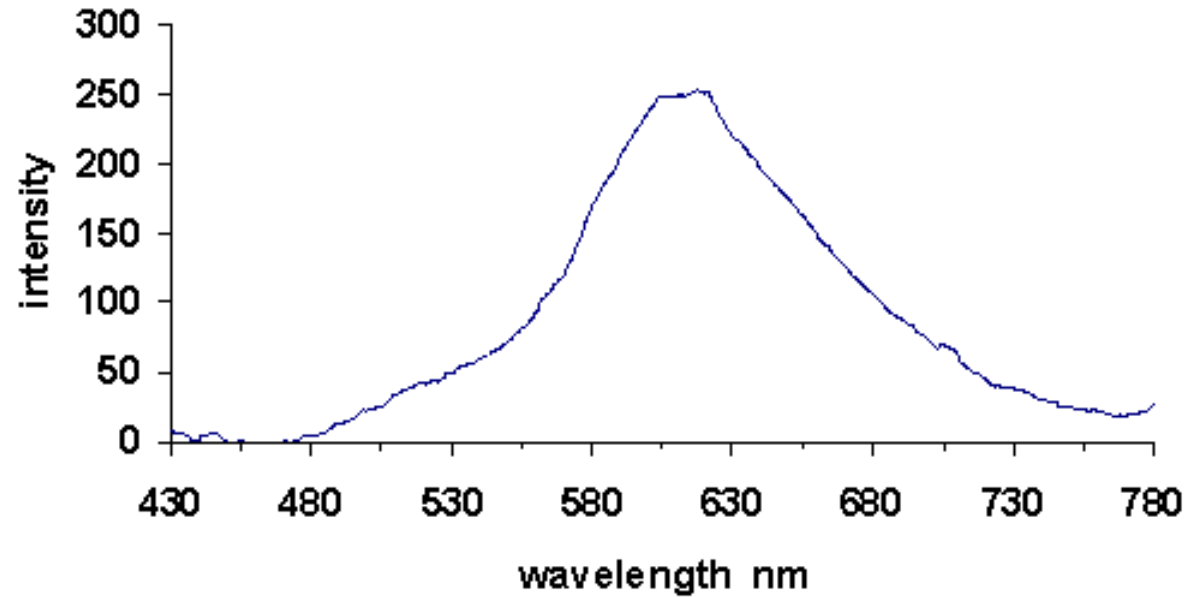


Compounding Nylon 11/15A Nile blue

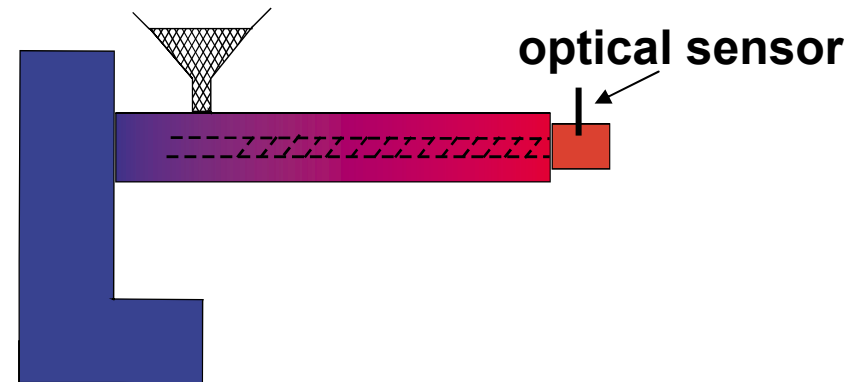
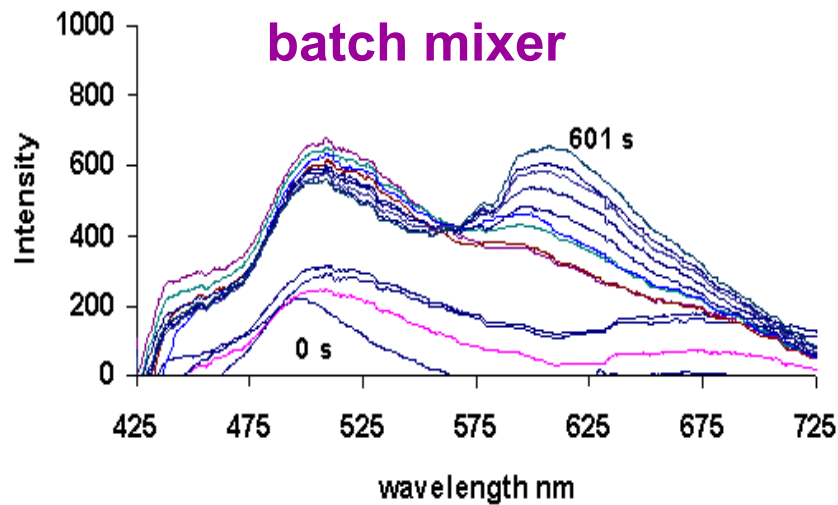


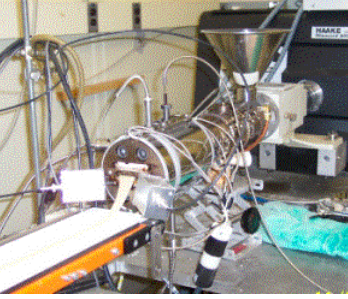
TEM from extrusion

twin screw compounding



batch mixer





Summary

- **The NIST Dielectric Slit Die**
- **Extent of exfoliation in nylon/clay nanocomposites from**
 - ◆ **Dielectric**
 - ◆ **Optical transmission**
 - ◆ **Fluorescence**
- **Measuring Extent of Exfoliation is prerequisite
for controlling exfoliation**